

Notice of References Cited

Application/Control No.

09/510,203

Applicant(s)/Patent Under

Reexamination

FIELDS ET AL.

Examiner

Ayal I Sharon

Art Unit

2123

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE Standard Dictionary of Electrical and Electronics Terms. Dec. 1996. p.1098. "test bed", "test bench".
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